

# LayTec to equip new RIBER cluster-tool for CIGS with multiple metrology systems

LayTec proudly announces that RIBER and its customer ZSW have chosen LayTec to supply a multi-station metrology system for monitoring and controlling CIGS (Cu(In,Ga)Se<sub>2</sub>) solar cell growth. The LayTec multi-station metrology system will monitor multiple deposition steps and will comprise both in-situ and in-line methods including spectral reflectance, emissivity-corrected pyrometry and photoluminescence. Beyond providing in-depth data for process analysis, the metrology systems will be directly embedded into the control software CRYSTAL XE of RIBER's automatic platform combining two clustered 4" MBE 412 systems, as well as further deposition technologies. With LayTec's metrology fully integrated into the new cluster tool, ZSW expects to get deep insights into the effects governing the deposition processes for the manufacturing of CIGS thin-film solar cells. Resulting further process improvements are intended to boost CIGS efficiency to values above 25%, i.e. beyond the current world record value of 23.4%.



**RIBER**

RIBER is a global market leader for semiconductor industry equipment. It designs and produces molecular beam epitaxy (MBE) systems as well as evaporation sources and cells for the semiconductor industry. Through its high-tech equipment, RIBER performs an essential role in the development of advanced semiconductor systems that are used in numerous consumer applications. [www.riber.com](http://www.riber.com)



ZSW (Zentrum für Sonnenenergie- und Wasserstoff-Forschung Baden-Württemberg in Stuttgart, Germany) is an industry-oriented research institute committed to research and development in the fields of photovoltaics, renewable energy sources, battery and fuel cell technologies. ZSW covers the entire industrial value chain, from materials research, prototype development and production processes to application systems, quality tests and market analyses. <https://www.zsw-bw.de/>



LayTec develops and manufactures integrated in-situ and in-line metrology for thin film deposition processes. Currently, the company has more than 2500 metrology systems installed worldwide and offers a global customer support and service network including local representations. [www.laytec.de](http://www.laytec.de)

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